



Fault Classification and Detection Using Artificial Intelligence

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Message from the Guest Editors

Dear Colleagues,

In order to run machine operations smoothly, machine faults need to be detected, located, and classified quickly. For this, artificial neural network approaches are considered significant tools in related applications of machine operations. Faults can occur in any machine or operation. They need to be identified in a timely manner, or else they can cause severe damage to operations. This special issue focuses on fault detection and classification using an intelligent approach of artificial neural networks applied to different sectors. The Special Issue will provide a single platform for researchers and industrialists to find research related to applications of AI for fault classification and detection in different sectors.

In this Special Issue, we invite submissions exploring cutting-edge research and recent advances in the area of fault classification and detection using artificial intelligence. We welcome both theoretical and experimental studies in this area that will be beneficial to the readers.





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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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